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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
09/607,675	06/30/2000	Robert B. Ogle JR.	P1025	1245	
24394	7590 12/28/2001				
LARIVIERE, GRUBMAN & PAYNE, LLP 1 LOWER RAGSDALE, BLDG. 1, SUITE 130 P.O. BOX 3140			EXAMINER		
			NGUYEN, CUONG QUANG		
MONTEREY	MONTEREY, CA 93942		ART UNIT	PAPER NUMBER	
			2811	6	
			DATE MAILED: 12/28/2001	DATE MAILED: 12/28/2001	

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)				
Offic Action Summary	09/607,675	OGLE ET AL.				
Onic Action Summary	Examiner	Art Unit				
The MAILING DATE of this communication app	Cuong Q Nguyen	the correspondence address				
Period for Reply						
A SHORTENED STATUTORY PERIOD FOR REPLY THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a reply - If NO period for reply is specified above, the maximum statutory period w - Failure to reply within the set or extended period for reply will, by statute, - Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	36(a). In no event, however, may a reply within the statutory minimum of thirty (3 will apply and will expire SIX (6) MONTH: cause the application to become ABAN	be timely filed 0) days will be considered timely. S from the mailing date of this communication. DONED (35 U.S.C. § 133).				
1) Responsive to communication(s) filed on						
·— ·						
,	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is					
closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.						
Disposition of Claims						
4) Claim(s) 1-13 is/are pending in the application.						
4a) Of the above claim(s) <u>6-13</u> is/are withdrawn from consideration.						
5) Claim(s) is/are allowed.						
6)⊠ Claim(s) <u>1-5</u> is/are rejected.						
7) Claim(s) is/are objected to.						
8) Claim(s) are subject to restriction and/o	r election requirement.					
Application Papers						
9) The specification is objected to by the Examiner.						
10) ☐ The drawing(s) filed on is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.						
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).						
11) The proposed drawing correction filed on is: a) approved b) disapproved by the Examiner.						
If approved, corrected drawings are required in reply to this Office action. 12) The oath or declaration is objected to by the Examiner.						
Priority under 35 U.S.C. §§ 119 and 120						
•	a priority under 35 U.S.C. & 1	19(a)-(d) or (f)				
13) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of:						
1. Certified copies of the priority documents have been received.						
2. Certified copies of the priority documents have been received in Application No						
3. Copies of the certified copies of the priority documents have been received in this National Stage						
application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received.						
14) Acknowledgment is made of a claim for domestic priority under 35 U.S.C. § 119(e) (to a provisional application).						
a) ☐ The translation of the foreign language provisional application has been received. 15)☐ Acknowledgment is made of a claim for domestic priority under 35 U.S.C. §§ 120 and/or 121.						
Attachment(s)						
1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO-1449) Paper No(s)	5) D Notice of Info	mmary (PTO-413) Paper No(s) ormal Patent Application (PTO-152)				

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DETAILED ACTION

Election/Restriction

1. Applicant's election with traverse of Group I, claims 1-5 in Paper No.5 is acknowledged. Because applicant did not distinctly and specifically point out the supposed errors in the restriction requirement, the election has been treated as an election without traverse (MPEP § 818.03(a)).

Oath/Declaration

2. The oath/declaration filed on 06/30/00 is acceptable.

Claim Rejections - 35 USC § 103

- 3. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 1-5 are rejected under 35 U.S.C. 103(a) as being unpatentable over Su el al. (US 6,133,096) in view of Cho et al. (US 6,027,971).

Regarding claims 1, 2 and 4, Su et al. discloses a semiconductor memory device comprising: a silicon substrate (1) (Su et al.'s col.3, lines38-40) including a peripheral memory region (90) and a core memory region (70); a transistor formed on the peripheral memory region; one set of dual gate core memory structures (15) formed in

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the core memory region, the dual gate core memory structures (15) including a stacked layer arrangement of semiconductor layers (7, 10) and a dielectric material layer (9), the dual gate core memory structure having sidewall portions; sidewall spacer structures (21) of silicon nitride (Su el al.'s col.6 lines 13-18) formed on the sidewall portions of dual gate core memory structures. See Su el al. Fig.7B and Fig.15.

Su et al. does not explicitly teach that the silicon nitride for forming spacer structures (21) have the chemical formula of Si3N4.

Cho et al. discloses a semiconductor memory device comprising: a dual gate core memory structure (62) formed in the core memory region; a sidewall spacer structures (68) formed on sidewall portions of the dual gate core memory structures, wherein the sidewall spacer structure formed of silicon nitride (Si3N4). Cho's Fig.8A and col.5 lines 63-67.

It is known in the art and also taught by Cho that silicon nitride is usually preferred to Si3N4 in semiconductor device. Therefore, it would have been obvious to one of ordinary skill in the art to form sidewall spacer structures of silicon nitride (Si3N4) as taught by Cho et al.

It is noted that, claimed structure and structure formed by the combination of Su and Cho are identical, such that both structure include sidewall spacer structures formed from silicon nitride (Si3N4, an anti-reflective coating material). Therefore, it is inherent that, the sidewall spacer structures in above combined device is also capable

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to protect the stacked layer arrangement during etching operations and is compatible with ion implantation and salicidation fabrication process as claimed device.

When the structure recited in claims reference is substantially identical in structure or composition, or are produced by identical or substantially identical to that of the claims, claimed properties of functions are presumed to be inherent. In re Best,195 USPQ 430, 433 (CCPA 1977). 1990).

The expressions "dual-purpose" and "being used for lithographic patterning and for protecting said stacked layer arrangement during etching operations." In claims 1 and 4 are considered as intended use limitations and are not considered towards patentability. A recitation of the intended use of the claimed invention must result in a structural difference between the claimed invention and the prior art in order to patentability distinguish the claimed invention from the prior art. If the prior art structure is capable of performing the intended use, then it meets the claim. In a claim drawn to a process of making, the intended use must result in a manipulative difference as compared to the prior art. See *In re Casey*, 152 USPQ 235 (CCPA 1967) and *In re Otto*, 136 USPQ 458, 459 (CCPA 1963).

Regarding claims 3 and 5, Su el al. teaches that the silicon nitride spacer structures (21) being deposited in a thickness of 1000 angstroms. Su et al.'s col.6, lines 13-18.

Conclusion

- 4. Papers related to this application may be submitted to Technology center (TC) 2800 by facsimile transmission. Papers should be faxed to TC 2800 via the TC 2800 Fax center located in Crystal Plaza 4, room 4-C23. The faxing of such papers must conform with the notice published in the Official Gazette, 1096 OG 30 (November 15, 1989). The Group 2811 Fax Center number is (703) 308-7722 and 308-7724. The Group 2811 Fax Center is to be used only for papers related to Group 2811 applications.
- 5. Any inquiry concerning this communication or any earlier communication from the Examiner should be directed to CUONG Q NGUYEN whose telephone number is (703) 308-1293. The Examiner is in the Office generally between the hours of 6:30 AM to 5:00 PM (Eastern Standard Time) Monday through Thursday.
- 6. If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor TOM THOMAS who can be reached on (703) 308-2772. The fax phone number for the organization where this application or proceeding is assigned is (703) 308-7722 or 308-7724.
- 7. Any inquiry of a general nature or relating to the status of this application should be directed to the Technology Center Receptionists whose telephone number is 308-0956.

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